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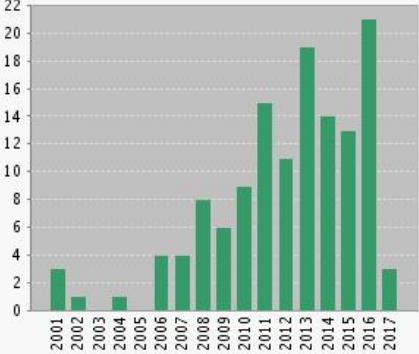
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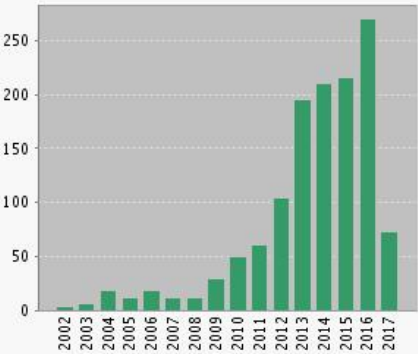
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Modeling and optimization of a solar energy harvester system for self-powered wireless sensor networks
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[IEEE TRANSACTIONS ON INDUSTRIAL ELECTRONICS](#) Volume: 55 Issue: 7 Pages: 2759-2766 Published: JUL 2008

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A Physical Model of the Temperature Dependence of the Current Through SiO2/HfO2 Stacks
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4.

Radiation effects on floating-gate memory cells
By: Cellere, G; Pellati, P; Chimenton, A; et al.
Conference: 38th Annual Nuclear and Space Radiation Effects Conference (NSREC) Location: VANCOUVER, CANADA Date: JUL 16-20, 2001 Sponsor(s): IEEE
[IEEE TRANSACTIONS ON NUCLEAR SCIENCE](#) Volume: 48 Issue: 6 Pages: 2222-2228 Article Number: PII S0018-9499(01)10715-X Part: 1 Published: DEC 2001

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Grain boundary-driven leakage path formation in HfO2 dielectrics
By: Bersuker, G.; Yum, J.; Vandelli, L.; et al.
Conference: 40th European Solid-State Device Research Conference (ESSDERC)/36th European Solid-State Circuits Conference (ESSCIRC)

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Carbon-doped GeTe: A promising material for Phase-Change Memories
By: Beneventi, G. Betti; Perniola, L.; Sousa, V.; et al.
Conference: 40th European Solid-State Device Research Conference (ESSDERC)/36th European Solid-State Circuits Conference (ESSCIRC)
Location: Seville, SPAIN Date: SEP 14-16, 2010
Sponsor(s): Univ Granada; Univ Seville, Inst Microelect Seville; EU Network Excellence NANOSIL; EUROSOL Network; IEEE Elect Device Soc
[SOLID-STATE ELECTRONICS](#) Volume: 65-66 Pages: 146-150 Published: NOV-DEC 2011

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Anomalous charge loss from floating-gate memory cells due to heavy ions irradiation
By: Cellere, G; Paccagnella, A; Larcher, L; et al.
Conference: 39th Annual International Nuclear and Space Radiation Effects Conference (NSREC) Location: PHOENIX, ARIZONA Date: JUL 15-19, 2002
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Pages: 3051-3058 Part: 1 Published: DEC 2002

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A 30.5 dBm 48% PAE CMOS class-E PA with integrated balun for RF applications
By: Brama, Riccardo; Larcher, Luca; Mazzanti, Andrea; et al.
Conference: IEEE Custom Integrated Circuits Conference Location: San Jose, CA Date: SEP 16-19, 2007
Sponsor(s): IEEE Solid State Circuits Soc; IEEE Electron Devices Soc
[IEEE JOURNAL OF SOLID-STATE CIRCUITS](#) Volume: 43 Issue: 8 Pages: 1755-1762 Published: AUG 2008

9.

A Compact Model of Program Window in HfOx RRAM Devices for Conductive Filament Characteristics Analysis
By: Larcher, Luca; Puglisi, Francesco Maria; Pavan, Paolo; et al.
[IEEE TRANSACTIONS ON ELECTRON DEVICES](#) Volume: 61 Issue: 8
Pages: 2668-2673 Published: AUG 2014

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An Empirical Model for RRAM Resistance in Low- and High-Resistance States
By: Puglisi, Francesco M.; Larcher, Luca; Bersuker, Gennadi; et al.
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